

Search Notes

Application/Control No.

10/536,910

Examiner

Winnie Yip

Applicant(s)/Patent under
Reexamination

HAN, IL

Art Unit

3636

SEARCHED

Class	Subclass	Date	Examiner
135	65 68 72 73	5/30/2006	WSY
		↓	↓
D3	7-8		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Text Searched in EAST system	5/30/2006	WSY